Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination TAKAYAMA ET AL.	
10/647,640		
Examiner	Art Unit	

2132

Benjamin E. Lanier

SEARCHED					
Class	Subclass	Date	Examiner		
			-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Limited Search of 713/168,170,173,176,178,181-186 705/64-66 See Attachment	5/23/2007	M
East Search See Attachment	5/23/2007	B
Inspec Search See Attachment	5/29/2007	B
EIC Fast and Focused Search See Attachment	45107	the state of the s
Inventor Name Search Palm	5/29/2007	Æ
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